Digital Control test in 1008

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Overview

- Test to change digital control.
- Checked each chip's hit rate and took the ratio run by run.
- Counting the number of clone hit chip by chip.

Overview

- I couldn't figure out the difference of hit rate ratio caused by the changing of digital control.
- Now I doubt that sending digital control doesn't work well.
- And chips which seem to be half entry still have clone hits.
- That's so mysterious.

6 runs with different digital control status

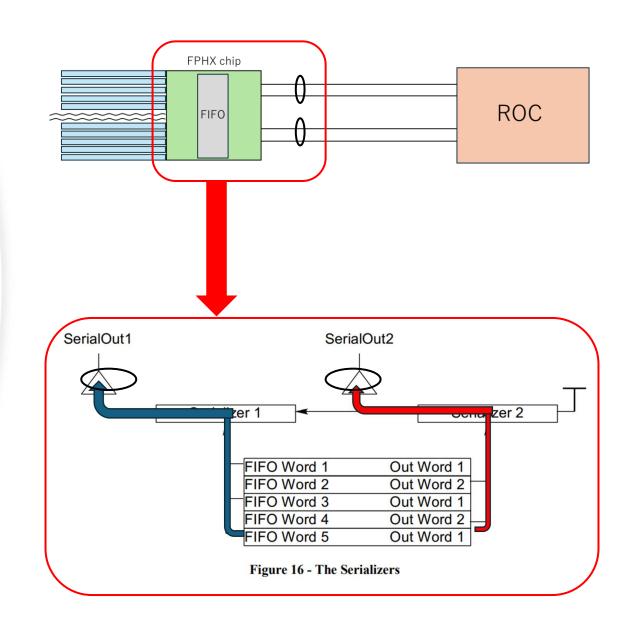
• We took 2 sets of noise data with 3 types of digital control.

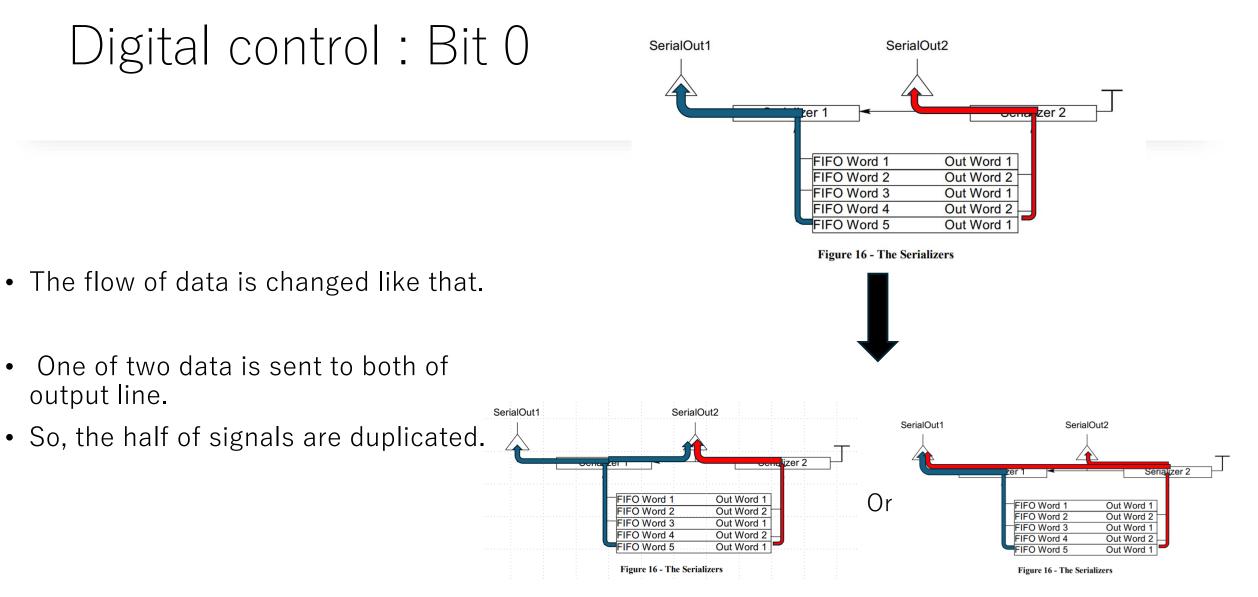
The function of digital control

- Digital control is a part of slow control with 4 bits.
- Bit 0 and 3 are changed in this test, since 1 and 2 have nothing to do with taking noise data.

Digital control : Bit 0

- Bit 0 is related with 2 output line from FPHX chip to ROC.
- Normally, it means set bit 0=1, FPHX chip sends data to ROC with 2 output line.
- When we set digital control bit 0=0, the way of sending data is changed.

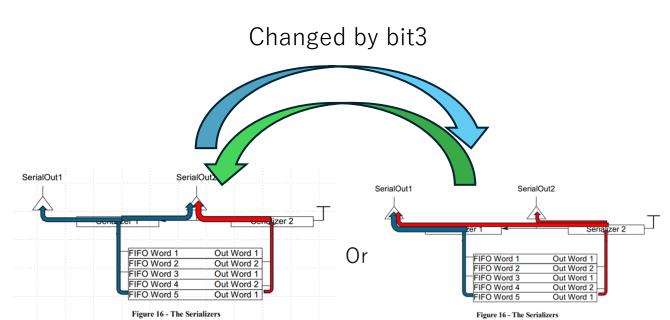




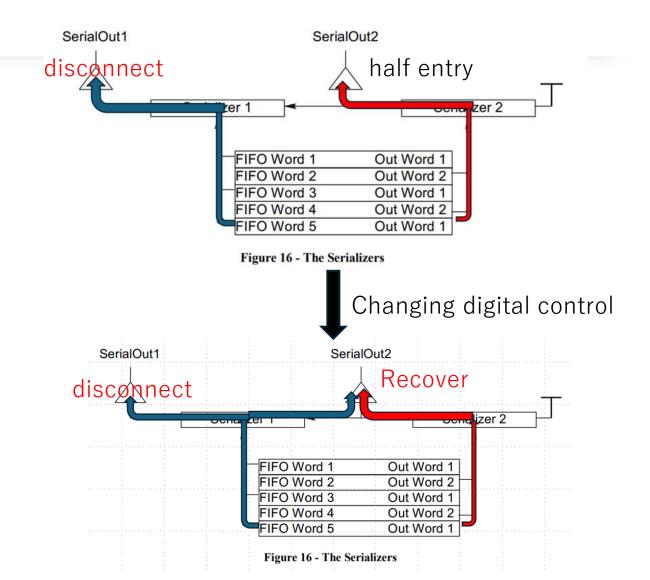
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Digital control : Bit 3

- Bit 3 is related to bit0=0.
- When bit0=0, one of two data is sent to both of output line.
- Then, bit3 can change which data to send other output line.
- But at present, we don't know which line is correspond to bit3=0 and bit3=1.



Half entry and digital control



- Half entry seems to be caused by the disconnection of one output line.
- If we set digital control bit0=0, one line starts to send both of two output lines data.
- It will recover the half entry chip.

The purpose of this test

- To recover half entry chip, we should know which bit0 and bit3 pair will work for each chip.
- Then, took noise data with 3 types of bit0 and bit3 pair.
- (bit3, bit2, bit1, bit0)=(0, 0, 0, 0), (0, 0, 0, 1), (1, 0, 0, 0)
- After this slide, I express (0, 0, 0, 0) as digcon=0, (0, 0, 0, 1) as digcon=1, (1, 0, 0, 0) as digcon=8.

What to check with each run

- Calculating hit rate chip by chip.
- Then, taking a ratio of them.

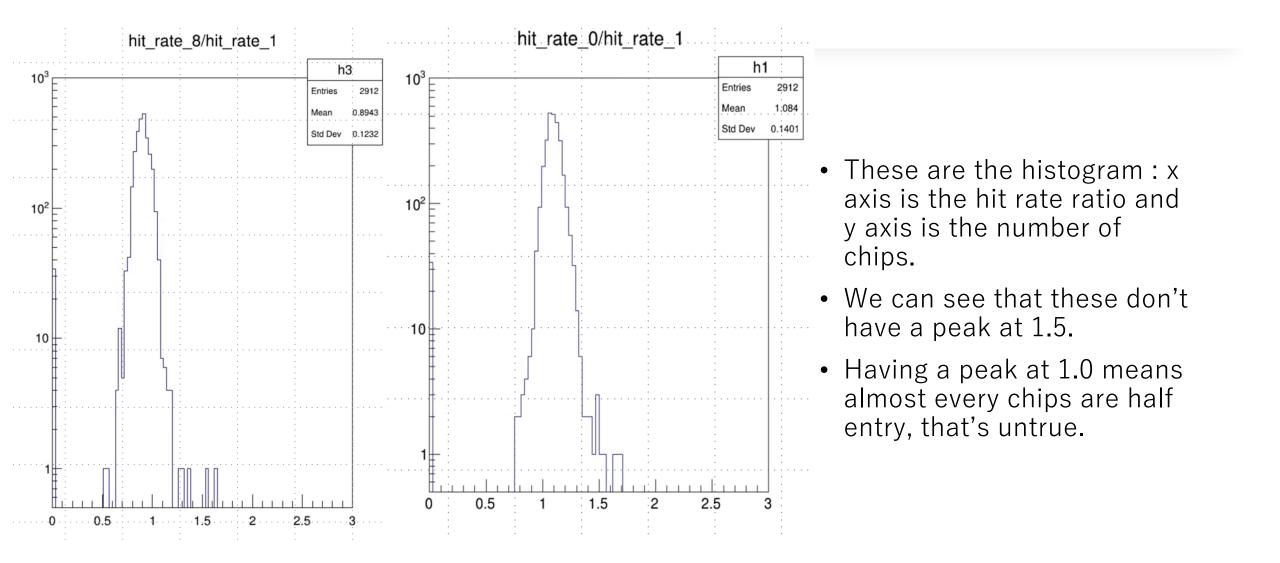
 $\rightarrow \frac{\text{hitrate}(\text{digcon}=0)}{\text{hitrate}(\text{digcon}=1)}, \frac{\text{hitrate}(\text{digcon}=8)}{\text{hitrate}(\text{digcon}=1)}$

• And also, counting clone hit chip by chip.

Hit rate ratio

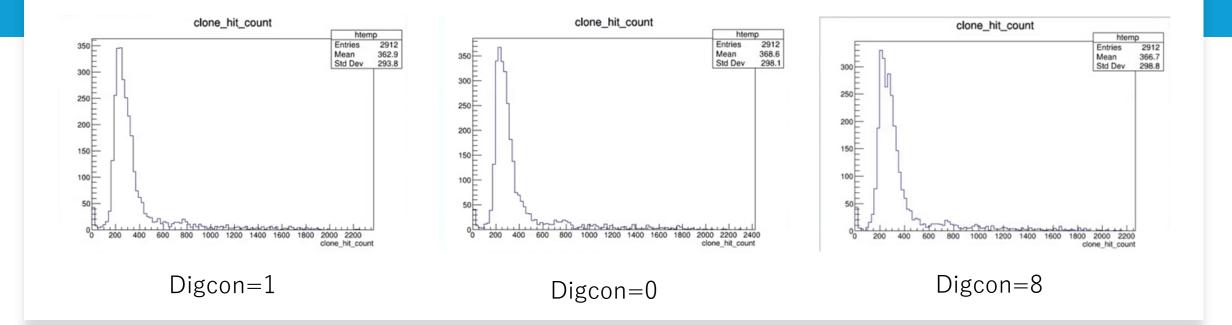
- Hitrate(digcon=0, 8) divided by hitrate(digcon=1) will have peaks depends on chip's status.
- If the chip is normal, changing digcon=1 to =0, 8 will increase hit ratio to $\frac{\text{hitrate}(\text{digcon}=0, 8)}{\text{hitrate}(\text{digcon}=1)} = 1.5$, since it duplicate one of two output line.
- If the chip is half entry, the ratio will be $\frac{\text{hitrate}(\text{digcon}=0 \text{ or } 8)}{\text{hitrate}(\text{digcon}=1)}=1.0 \text{ or } 2.0$
- We don't know which 0 or 8 recover half entry.

Results



Counting clone hit

- According to our hypothesis, changing digital control will increase clone hits on normal (not half entry) chip.
- All chips, except for masked chips, have almost same amount of clone hits.
- It's so mysterious why chips which seems to be half entry still contain clone hits.



Results

- The measurement time is almost same, so the count is also the rate of clone hit.
- We cannot see any increasing of clone hit.

Results

- I also calculated the clone hit ratio $\frac{total\ clone\ hit}{total\ hit}$, but there're also no difference.

Conclusion

- We took noise data with changing digital control, but I hardly see the difference in both hit rate and clone hit count.
- Furthermore, chips which seems to be half entry also contain clone hit.
- My questions are

Does digital control really work?

Are they half entry chips same as tested in RIKEN testbench (It means they're just poor efficiency chips, not half output line dead)?

